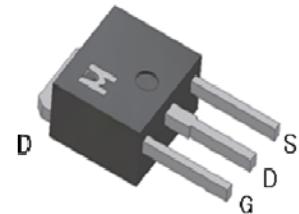
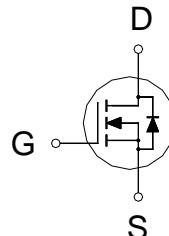


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV <sub>DSS</sub>	250V
R <sub>DSON</sub> (MAX.)	1.7 Ω
I <sub>D</sub>	3.0A



UIS, R<sub>G</sub> 100% Tested

Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±20	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	3.0	A
	T <sub>C</sub> = 100 °C		1.9	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	12	
Avalanche Current		I <sub>AS</sub>	1	
Avalanche Energy	L = 3mH, ID=1A, RG=25 Ω	E <sub>AS</sub>	1.5	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 1mH	E <sub>AR</sub>	0.5	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	30	W
	T <sub>C</sub> = 100 °C		13	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	4.2	4.2	°C / W
Junction-to-Ambient	R <sub>θJA</sub>		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 10\text{mA}$	250			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.0	2.0	3.0	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 200V, V_{GS} = 0V$			1	$\mu\text{A}$
		$V_{DS} = 200V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	3.3			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 1.5A$		1.35	1.7	$\Omega$
		$V_{GS} = 5V, I_D = 0.8A$		1.5	2.0	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 50V, I_D = 1.5A$		2.0		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$		680		pF
Output Capacitance	$C_{oss}$			15		
Reverse Transfer Capacitance	$C_{rss}$			13		
Gate Resistance	$R_g$	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		3.0		$\Omega$
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 200V, V_{GS} = 10V, I_D = 1.5A$		17.8		nC
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			2.2		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			4.4		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(\text{on})}$	$V_{DS} = 125V, I_D = 1A, V_{GS} = 10V, R_G = 6\Omega$		10		nS
Rise Time <sup>1,2</sup>	$t_r$			40		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(\text{off})}$			12		
Fall Time <sup>1,2</sup>	$t_f$			20		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				3	A
Pulsed Current <sup>3</sup>	$I_{SM}$				12	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	$t_{rr}$	$I_F = 3A, dI_F/dt = 100A/\mu\text{s}$		110		nS
Reverse Recovery Charge	$Q_{rr}$			350		nC

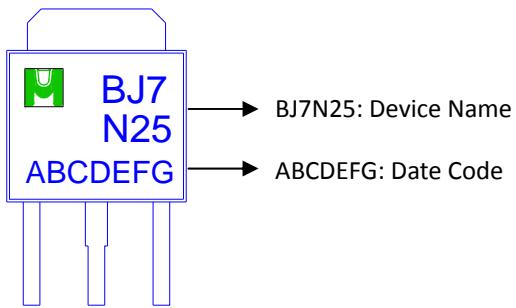
<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

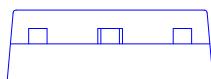
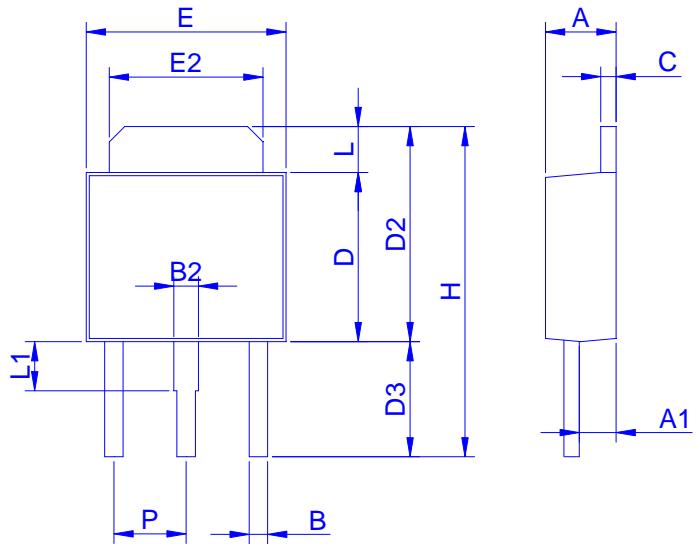
<sup>3</sup>Pulse width limited by maximum junction temperature.

#### Ordering & Marking Information:

Device Name: EMBJ7N25CS for IPAK (TO-251)



#### Outline Drawing



#### Dimension in mm

Dimension	A	A1	B	B2	C	D	D2	D3	E	E2	H	L	L1	P
Min.	2.10	0.90	0.40	0.60	0.40	5.30	6.70	3.40	6.30	4.80	10.2	0.89	0.90	2.10
Max.	2.50	1.50	0.90	1.15	0.60	6.25	7.30	4.30	6.80	5.50	11.5	1.40	1.80	2.50



TYPICAL CHARACTERISTICS

